STL8N10F7



N-channel 100 V, 17 mΩ typ., 8 A STripFET™ F7 Power MOSFET in a PowerFLAT™ 3.3x3.3 package

Datasheet - production data

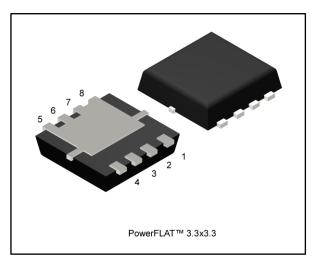
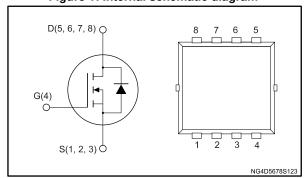


Figure 1: Internal schematic diagram



Features

| Order code | V _{DS} | R _{DS(on)} max. | ΙD | Ртот |
|------------|-----------------|--------------------------|-----|-------|
| STL8N10F7 | 100 V | 20 mΩ | 8 A | 2.9 W |

- Among the lowest R_{DS(on)} on the market
- Excellent FoM (figure of merit)
- Low C_{rss}/C_{iss} ratio for EMI immunity
- High avalanche ruggedness

Applications

• Switching applications

Description

This N-channel Power MOSFET utilizes STripFET™ F7 technology with an enhanced trench gate structure that results in very low onstate resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.

Table 1: Device summary

| Order code | Marking | Package | Packing |
|------------|---------|--------------------|---------------|
| STL8N10F7 | 8N10F | PowerFLAT™ 3.3x3.3 | Tape and reel |

Contents STL8N10F7

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STL8N10F7 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|-----------------------------------|---|------------|------|
| V _{DS} | Drain-source voltage | 100 | V |
| V_{GS} | Gate-source voltage | ±20 | V |
| I _D ⁽¹⁾ | Drain current (continuous) at T _{pcb} = 25 °C | 8 | Α |
| I _D ⁽¹⁾ | Drain current (continuous) at T _{pcb} = 100 °C | 6 | Α |
| I _D ⁽²⁾ | Drain current (continuous) at T _c = 25 °C | 35 | Α |
| I _D ⁽²⁾ | Drain current (continuous) at Tc= 100 °C | 22 | Α |
| I _{DM} ⁽¹⁾⁽³⁾ | Drain current (pulsed) | 32 | Α |
| I _{DM} ⁽²⁾⁽³⁾ | Drain current (pulsed) | 140 | Α |
| P _{TOT} ⁽²⁾ | Total dissipation at T _C = 25 °C | 50 | W |
| P _{TOT} ⁽¹⁾ | Total dissipation at T _{pcb} = 25 °C | 2.9 | W |
| T_{stg} | Storage temperature range | FF to 150 | °C |
| Tj | Operating junction temperature range | -55 to 150 | °C |

Notes:

Table 3: Thermal data

| Symbol | Parameter | Value | Unit |
|-------------------------------------|--------------------------------------|-------|--------|
| R _{thj-case} | Thermal resistance junction-case | 2.5 | °C/W |
| R _{thj-pcb} ⁽¹⁾ | Thermal resistance junction-pcb 42.8 | | - C/VV |

Notes

 $^{(1)}$ When mounted on FR-4 board of 1inch², 2oz Cu, t < 10 s.

 $^{^{(1)}\}mbox{This}$ value is rated according to Rthj-pcb.

 $^{^{(2)}}$ This value is rated according to $R_{thj\text{-}case}$.

 $[\]ensuremath{^{(3)}}\mbox{Pulse}$ width limited by safe operating area.

Electrical characteristics STL8N10F7

2 Electrical characteristics

(T_C= 25 °C unless otherwise specified)

Table 4: Static

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|---------------------|------------------------------------|---|------|------|------|------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage | $V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$ | 100 | | | ٧ |
| | Zaro goto voltago droin | $V_{GS} = 0 \text{ V}, V_{DS} = 100 \text{ V}$ | | | 1 | μΑ |
| IDSS | Zero gate voltage drain current | $V_{GS} = 0 \text{ V}, V_{DS} = 100 \text{ V},$ $T_{c} = 125 \text{ °C}$ (1) | | | 100 | μΑ |
| I _{GSS} | Gate-body leakage current | $V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$ | | | ±100 | nA |
| V _{GS(th)} | Gate threshold voltage | $V_{DS} = V_{GS}$, $I_D = 250 \mu A$ | 2.5 | | 4.5 | V |
| R _{DS(on)} | Static drain-source on-resistance | V _{GS} = 10 V, I _D = 4 A | | 17 | 20 | mΩ |

Notes:

Table 5: Dynamic

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|----------|------------------------------|---|------|------|------|------|
| Ciss | Input capacitance | | ı | 1640 | 1 | pF |
| Coss | Output capacitance | V _{DS} = 50 V, f = 1 MHz, | ı | 360 | 1 | pF |
| Crss | Reverse transfer capacitance | $V_{GS} = 0 V$ | ı | 25 | ı | pF |
| Q_g | Total gate charge | $V_{DD} = 50 \text{ V}, I_D = 8 \text{ A},$ | ı | 25 | 1 | nC |
| Q_{gs} | Gate-source charge | V _{GS} = 0 to 10 V (see <i>Figure 14: "Test circuit for</i> | ı | 12 | 1 | nC |
| Q_{gd} | Gate-drain charge | gate charge behavior") | ı | 5 | ı | nC |

Table 6: Switching times

| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|---------------------|---------------------|---|------|------|------|------|
| t _{d(on)} | Turn-on delay time | $V_{DD} = 50 \text{ V}, I_D = 4 \text{ A},$ | 1 | 15 | - | ns |
| tr | Rise time | R _G = 4.7 Ω , V _{GS} = 10 V (see Figure 13: "Test circuit for | 1 | 17 | - | ns |
| t _{d(off)} | Turn-off-delay time | resistive load switching times" and Figure 18: "Switching time waveform") | - | 24 | - | ns |
| tf | Fall time | | 1 | 8 | - | ns |

 $^{^{(1)}\}mbox{Defined}$ by design, not subject to production test.

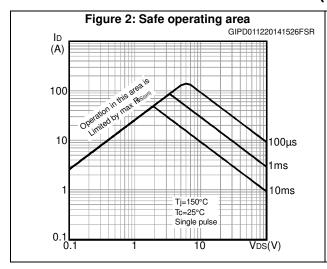
Table 7: Source-drain diode

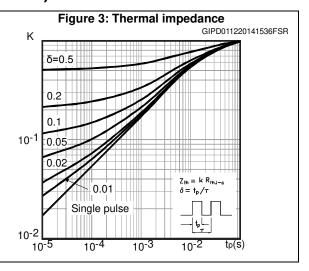
| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|---------------------|--------------------------|--|------|------|------|------|
| V _{SD} (1) | Forward on voltage | V _{GS} = 0 V, I _{SD} = 8 A | - | | 1.1 | V |
| t _{rr} | Reverse recovery time | $I_{SD} = 8 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$ | 1 | 53 | | ns |
| Qrr | Reverse recovery charge | $V_{DD} = 80 \text{ V}, T_j = 150 \text{ °C}$ (see Figure 15: "Test circuit for | 1 | 67 | | nC |
| I _{RRM} | Reverse recovery current | inductive load switching and diode recovery times") | - | 2.5 | | Α |

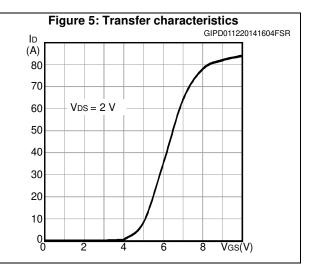
Notes:

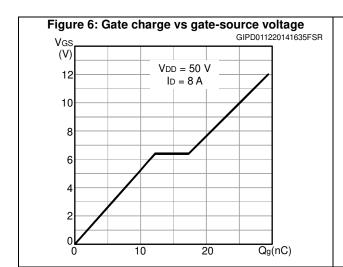
 $^{^{(1)}\}text{Pulse}$ test: pulse duration = 300 $\mu\text{s},$ duty cycle 1.5%

2.1 Electrical characteristics (curves)









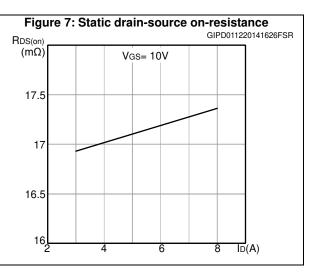


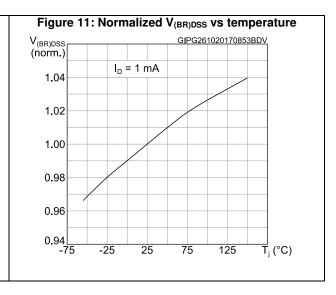
Figure 8: Capacitance variations

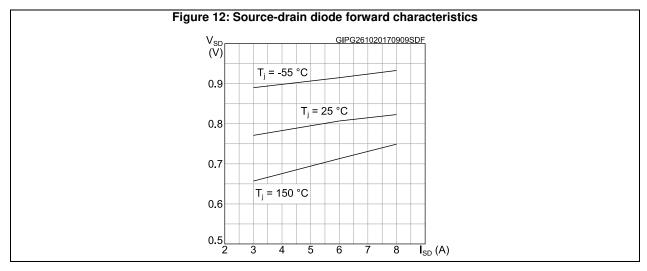
Coss

Co

Figure 9: Normalized gate threshold voltage vs temperature V_{GS(th)} (norm.) GIPG261020170852VTH I_D=250 μA 1.1 1.0 0.9 0.8 0.7 0.6 -75 -25 25 75 125 T_J(℃)

Figure 10: Normalized on-resistance vs temperature $R_{DS(on)}$ (norm.) $V_{GS} = 10 \text{ V}$ $I_D = 4 \text{ V}$ $I_{D} = 4$





Test circuits STL8N10F7

3 Test circuits

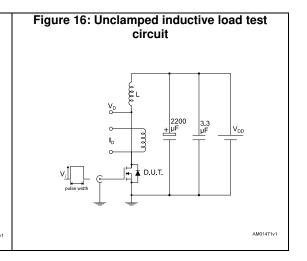
Figure 13: Test circuit for resistive load switching times

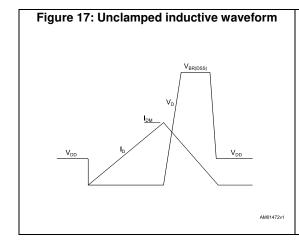
Figure 14: Test circuit for gate charge behavior

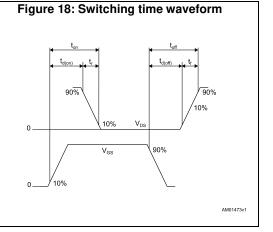
12 V 47 kΩ 100 nF D.U.T.

2200 PF 47 kΩ OVG

AM01466y1







STL8N10F7 Package information

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

4.1 PoweFLAT 3.3x3.3 pakage information

Figure 19: PowerFLAT™ 3.3x3.3 package outline

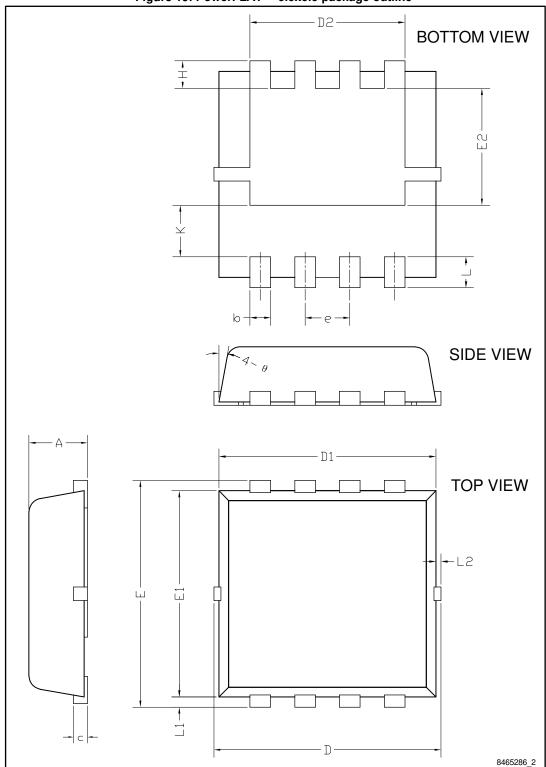
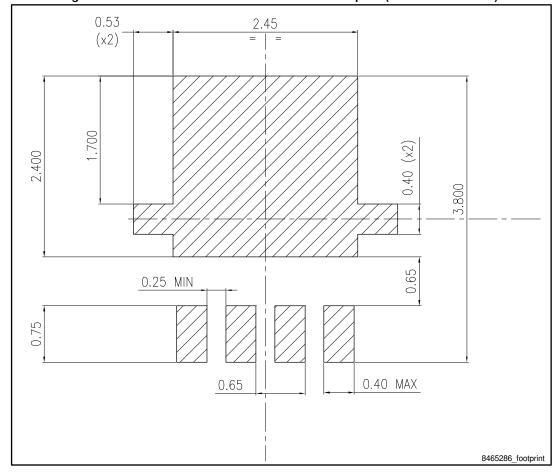


Table 8: PowerFLAT™ 3.3x3.3 package mechanical data

| Dim. | | mm | |
|--------|------|------|------|
| Dilli. | Min. | Тур. | Max. |
| Α | 0.70 | 0.80 | 0.90 |
| b | 0.25 | 0.30 | 0.39 |
| С | 0.14 | 0.15 | 0.20 |
| D | 3.10 | 3.30 | 3.50 |
| D1 | 3.05 | 3.15 | 3.25 |
| D2 | 2.15 | 2.25 | 2.35 |
| е | 0.55 | 0.65 | 0.75 |
| E | 3.10 | 3.30 | 3.50 |
| E1 | 2.90 | 3.00 | 3.10 |
| E2 | 1.60 | 1.70 | 1.80 |
| Н | 0.25 | 0.40 | 0.55 |
| K | 0.65 | 0.75 | 0.85 |
| L | 0.30 | 0.45 | 0.60 |
| L1 | 0.05 | 0.15 | 0.25 |
| L2 | | | 0.15 |
| θ | 8° | 10° | 12° |

Figure 20: PowerFLAT™ 3.3x3.3 recommended footprint (dimensions in mm)



STL8N10F7 Revision history

5 Revision history

Table 9: Document revision history

| Date | Revision | Changes |
|-------------|----------|---|
| 31-Jul-2013 | 1 | First release. |
| 05-Dec-2014 | 2 | Document status promoted from preliminary to production data. Modified title, features and description in cover page. Modified: R _{DS(on)} typical and max values in first page and in <i>Table 4: On/off states</i> Modified: Section 4: Package mechanical data Added Section 2.1: Electrical characteristics (curves). |
| 02-Nov-2017 | 3 | Datasheet promoted from preliminary data to production data. Modified title, silhouette and features table on cover page. Modified Table 2: "Absolute maximum ratings", Table 4: "Static" and Table 5: "Dynamic". Modified Figure 8: "Capacitance variations", Figure 9: "Normalized gate threshold voltage vs temperature", Figure 10: "Normalized onresistance vs temperature", Figure 11: "Normalized V(BR)DSS vs temperature" and Figure 12: "Source-drain diode forward characteristics". Updated Section 4: "Package information". Minor text changes. |

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